



## AO3403

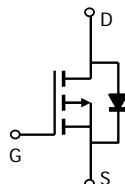
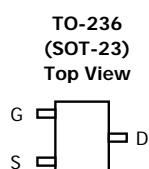
### P-Channel Enhancement Mode Field Effect Transistor

#### General Description

The AO3403 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard Product AO3403 is Pb-free (meets ROHS & Sony 259 specifications). AO3403L is a Green Product ordering option. AO3403 and AO3403L are electrically identical.

#### Features

$V_{DS}$  (V) = -30V  
 $I_D$  = -2.6 A ( $V_{GS}$  = -10V)  
 $R_{DS(ON)} < 130\text{m}\Omega$  ( $V_{GS}$  = -10V)  
 $R_{DS(ON)} < 180\text{m}\Omega$  ( $V_{GS}$  = -4.5V)  
 $R_{DS(ON)} < 260\text{m}\Omega$  ( $V_{GS}$  = -2.5V)



#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-2.6	A
$T_A=70^\circ\text{C}$		-2.2	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	-20	
Power Dissipation <sup>A</sup>	$P_D$	1.4	W
$T_A=70^\circ\text{C}$		1	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	70	90	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		100	125	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	63	80	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.6	-1	-1.4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-10			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-2.6\text{A}$ $T_J=125^\circ\text{C}$		102	130	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		154	200	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$		128	180	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-2.5\text{A}$	3	4.5		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.85	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		409	500	pF
$C_{\text{oss}}$	Output Capacitance			55		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			42		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		12	16	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-15\text{V}, I_D=-2.5\text{A}$		4.4	5.3	nC
$Q_{\text{gs}}$	Gate Source Charge			0.8		nC
$Q_{\text{gd}}$	Gate Drain Charge			1.32		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=6\Omega, R_{\text{GEN}}=3\Omega$		5.3	8	ns
$t_r$	Turn-On Rise Time			4.4	9	ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			31.5	45	ns
$t_f$	Turn-Off Fall Time			8	16	ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-2.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		15.8	19	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-2.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8	12	nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $\leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

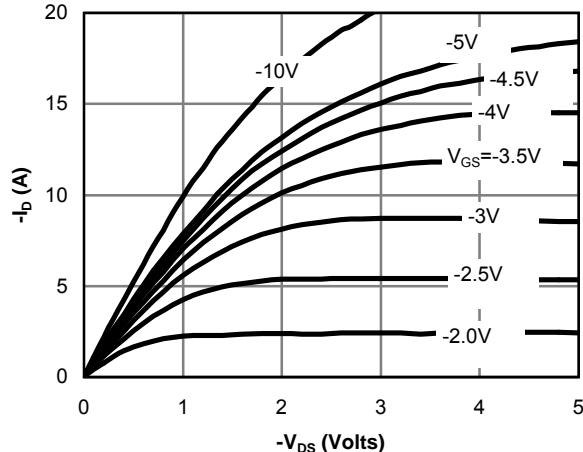


Fig 1: On-Region Characteristics

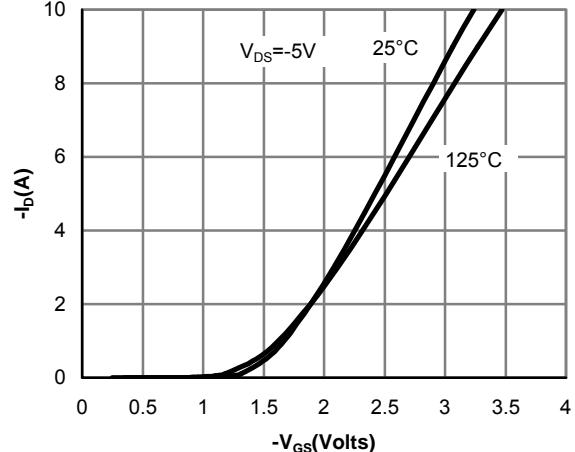


Figure 2: Transfer Characteristics

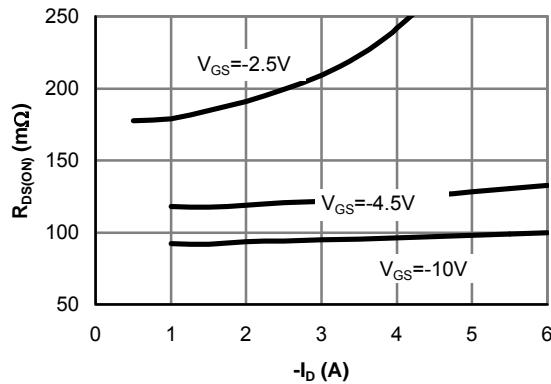


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

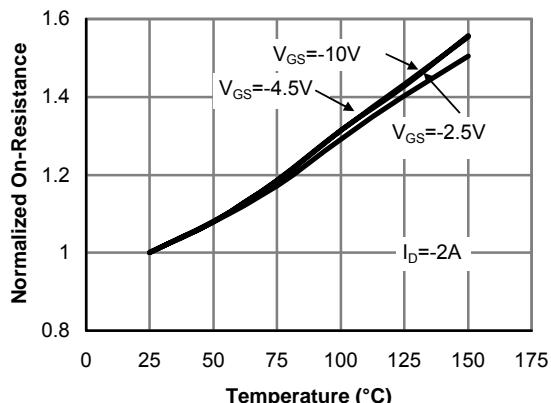


Figure 4: On-Resistance vs. Junction Temperature

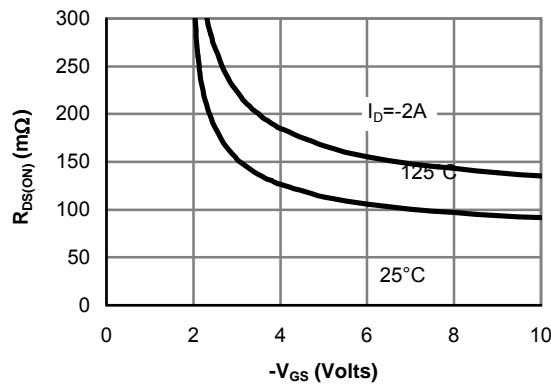


Figure 5: On-Resistance vs. Gate-Source Voltage

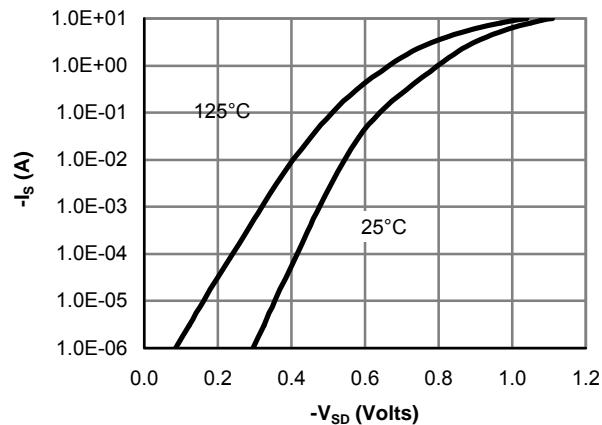


Figure 6: Body-Diode Characteristics

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